

NCE N-Channel Enhancement Mode Power MOSFET

Description

The NCE0125AI uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge. It can be used in a wide variety of applications.

General Features

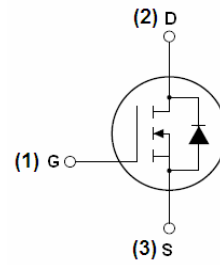
- $V_{DS} = 100V, I_D = 25A$
 $R_{DS(ON)} < 36m\Omega @ V_{GS}=10V$ (Typ:31 m Ω)
- Special process technology for high ESD capability
- High density cell design for ultra low R_{dson}
- Fully characterized avalanche voltage and current
- Good stability and uniformity with high E_{AS}
- Excellent package for good heat dissipation

Application

- Power switching application
- Hard switched and high frequency circuits
- Uninterruptible power supply

100% UIS TESTED!

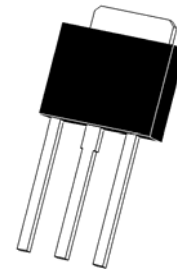
100% ΔV_d s TESTED!



Schematic diagram



Marking and pin assignment



TO-251 top view

Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
NCE0125AI	NCE0125AI	TO-251	-	-	-

Absolute Maximum Ratings ($T_C=25^\circ C$ unless otherwise noted)

Symbol	Parameter	Limit	Unit
V_{DS}	Drain-Source Voltage	100	V
V_{GS}	Gate-Source Voltage	± 20	V
I_D	Drain Current-Continuous	25	A
$I_D(100^\circ C)$	Drain Current-Continuous($T_C=100^\circ C$)	17.6	A
I_{DM}	Pulsed Drain Current	70	A
P_D	Maximum Power Dissipation	70	W
	Derating factor	0.5	W/ $^\circ C$
E_{AS}	Single pulse avalanche energy ^(Note 5)	110	mJ
T_J, T_{STG}	Operating Junction and Storage Temperature Range	-55 To 175	$^\circ C$

Thermal Characteristic

$R_{\theta JC}$	Thermal Resistance, Junction-to-Case ^(Note 2)	2	$^{\circ}C/W$
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Electrical Characteristics ($T_C=25^{\circ}C$ unless otherwise noted)

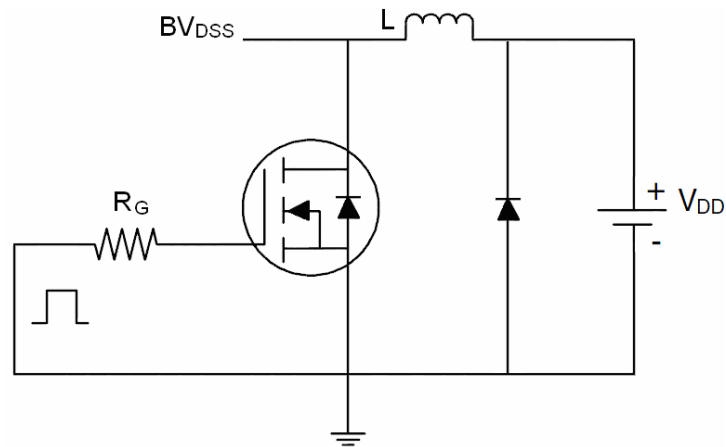
Symbol	Parameter	Condition	Min	Typ	Max	Unit
Off Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=250\mu A$	100	110	-	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=100V, V_{GS}=0V$	-	-	1	μA
I_{GSS}	Gate-Body Leakage Current	$V_{GS}=\pm 20V, V_{DS}=0V$	-	-	± 100	nA
On Characteristics ^(Note 3)						
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu A$	1.0	1.6	2.2	V
$R_{DS(ON)}$	Drain-Source On-State Resistance	$V_{GS}=10V, I_D=15A$	-	31	36	m Ω
g_{FS}	Forward Transconductance	$V_{DS}=5V, I_D=15A$	-	12	-	S
Dynamic Characteristics ^(Note 4)						
C_{iss}	Input Capacitance	$V_{DS}=50V, V_{GS}=0V,$ $F=1.0MHz$	-	3000	-	PF
C_{oss}	Output Capacitance		-	92	-	PF
C_{rSS}	Reverse Transfer Capacitance		-	18.3	-	PF
Switching Characteristics ^(Note 4)						
$t_{d(on)}$	Turn-on Delay Time	$V_{DD}=50V, R_L=5\Omega$ $V_{GS}=10V, R_{GEN}=3\Omega$	-	9	-	nS
t_r	Turn-on Rise Time		-	9	-	nS
$t_{d(off)}$	Turn-Off Delay Time		-	31	-	nS
t_f	Turn-Off Fall Time		-	9	-	nS
Q_g	Total Gate Charge	$V_{DS}=50V, I_D=25A,$ $V_{GS}=10V$	-	70.4	-	nC
Q_{gs}	Gate-Source Charge		-	9.0	-	nC
Q_{gd}	Gate-Drain Charge		-	15.3	-	nC
Drain-Source Diode Characteristics						
V_{SD}	Diode Forward Voltage ^(Note 3)	$V_{GS}=0V, I_S=25A$	-	-	1.2	V
I_S	Diode Forward Current ^(Note 2)	-	-	-	25	A
t_{rr}	Reverse Recovery Time	$T_J = 25^{\circ}C, I_F = 25A$ $di/dt = 100A/\mu s$ ^(Note 3)	-	34	-	nS
Q_{rr}	Reverse Recovery Charge		-	56	-	nC

Notes:

1. Repetitive Rating: Pulse width limited by maximum junction temperature.
2. Surface Mounted on FR4 Board, $t \leq 10$ sec.
3. Pulse Test: Pulse Width $\leq 300\mu s$, Duty Cycle $\leq 2\%$.
4. Guaranteed by design, not subject to production
5. EAS Condition : $T_J=25^{\circ}C, V_{DD}=50V, V_G=10V, L=0.5mH, R_g=25\Omega$

Test Circuit

1) E_{AS} Test Circuit



2) Gate Charge Test Circuit



3) Switch Time Test Circuit



Typical Electrical and Thermal Characteristics (Curves)

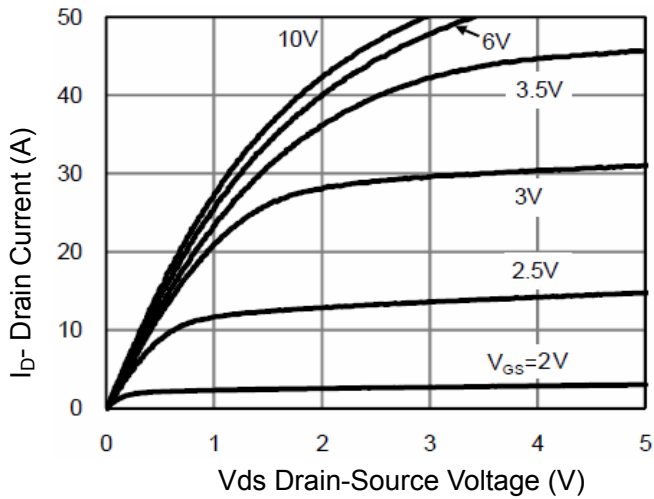


Figure 1 Output Characteristics

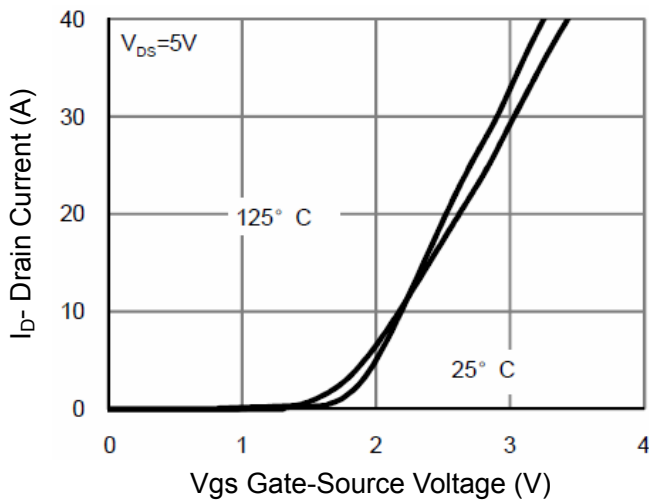


Figure 2 Transfer Characteristics

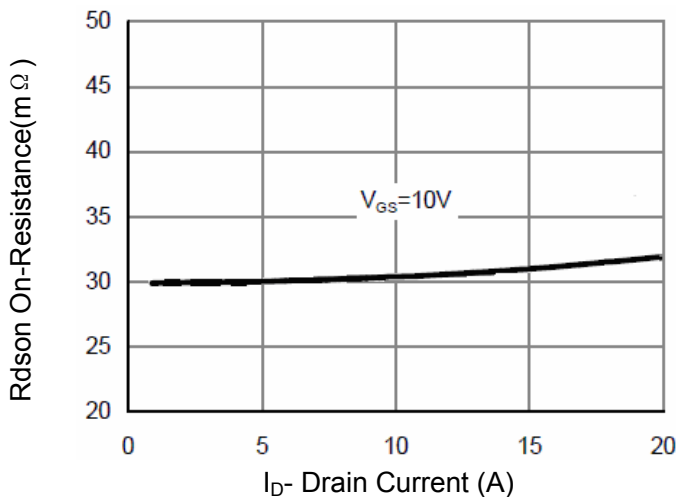


Figure 3 Rdson- Drain Current

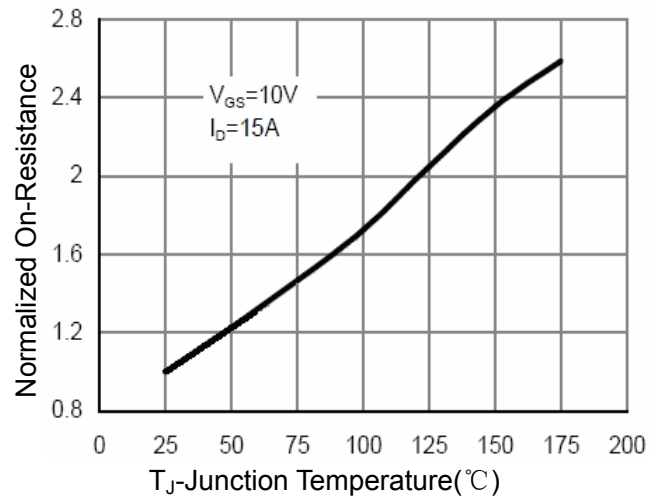


Figure 4 Rdson-Junction Temperature

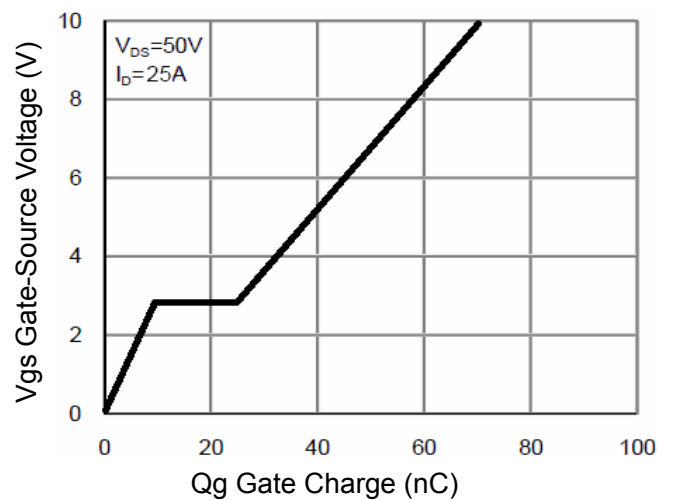


Figure 5 Gate Charge

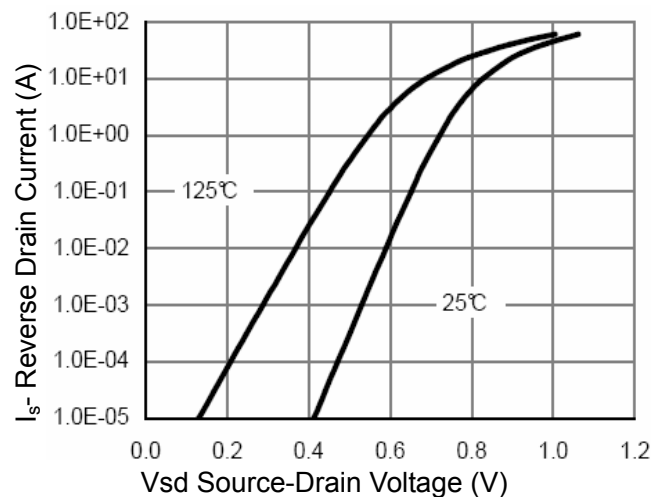


Figure 6 Source- Drain Diode Forward

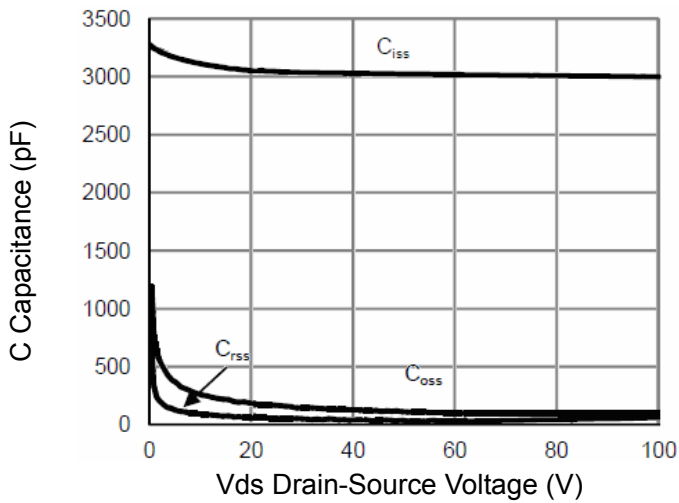


Figure 7 Capacitance vs Vds

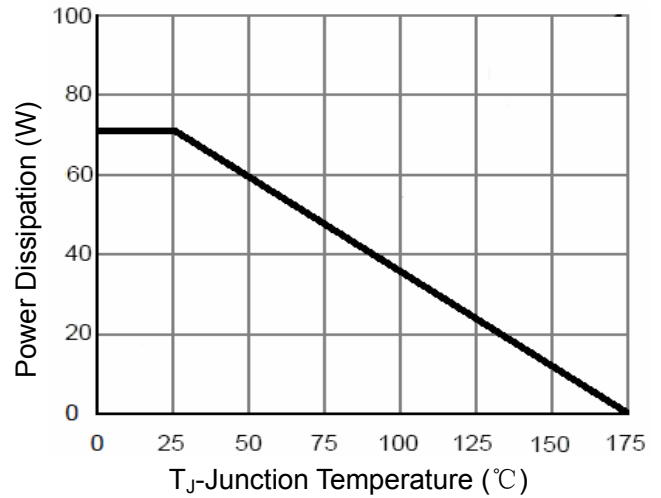


Figure 9 Power De-rating

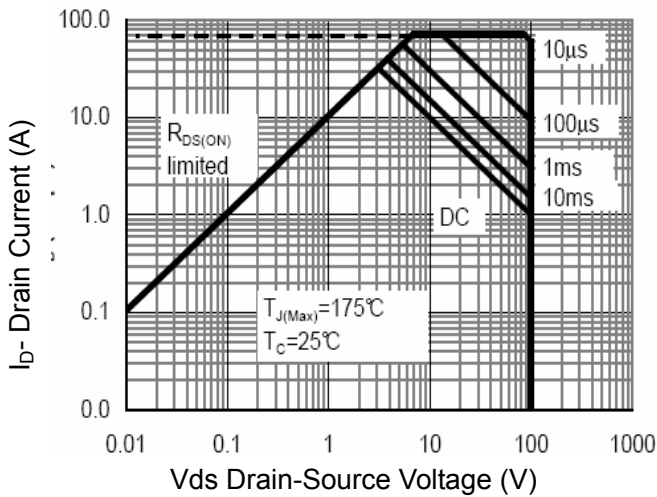


Figure 8 Safe Operation Area

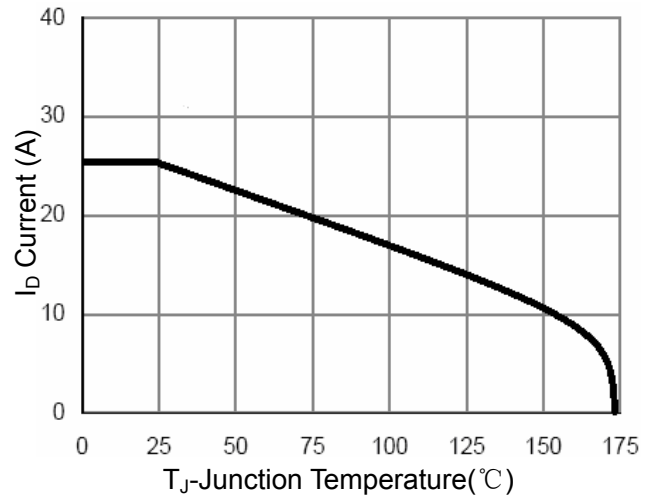


Figure 10 ID Current- Junction Temperature

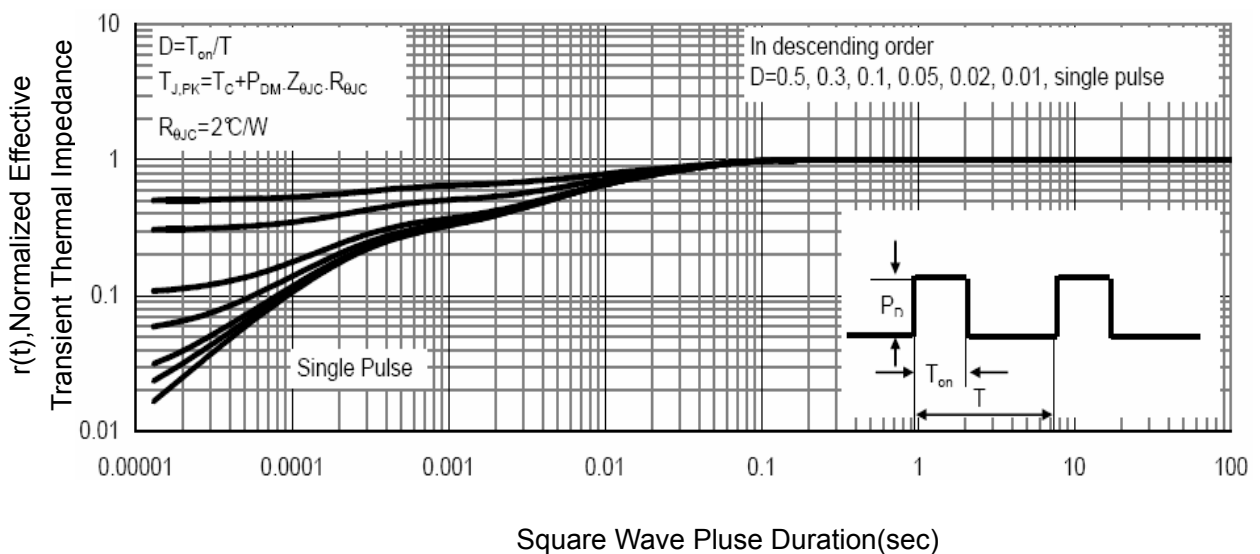
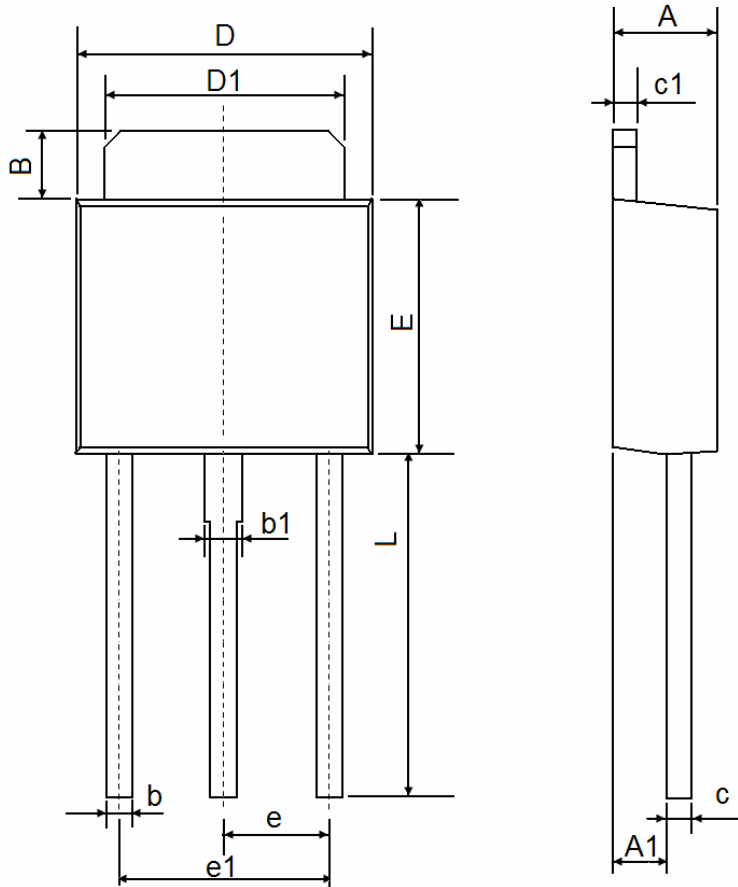


Figure 11 Normalized Maximum Transient Thermal Impedance

TO-251 Package Information


Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	2.200	2.400	0.087	0.094
A1	1.050	1.350	0.042	0.054
B	1.350	1.650	0.053	0.065
b	0.500	0.700	0.020	0.028
b1	0.700	0.900	0.028	0.035
c	0.430	0.580	0.017	0.023
c1	0.430	0.580	0.017	0.023
D	6.350	6.650	0.250	0.262
D1	5.200	5.400	0.205	0.213
E	5.400	5.700	0.213	0.224
e	2.300 TYP		0.091 TYP	
e1	4.500	4.700	0.177	0.185
L	7.500	7.900	0.295	0.311

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